

<b>Notice of References Cited</b>	Application/Control No. 10/662,394		Applicant(s)/Patent Under Reexamination AKIYAMA ET AL.	
	Examiner DANNY W. LEUNG		Art Unit 2613	Page 1 of 4

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,327,511 A	07-1994	Heismann et al.	385/1
*	B	US-5,659,412 A	08-1997	Hakki, Basil Wahid	398/152
*	C	US-5,930,414 A	07-1999	Fishman et al.	385/11
*	D	US-5,949,560 A	09-1999	Roberts et al.	398/29
*	E	US-5,994,898 A	11-1999	DiMarzio et al.	324/244.1
*	F	US-5,986,746 A	11-1999	Metz et al.	356/71
*	G	US-6,097,525 A	08-2000	Ono et al.	398/185
*	H	US-6,130,766 A	10-2000	Cao, Xiang-Dong	398/147
*	I	US-6,154,273 A	11-2000	Suzuki, Yasuo	356/73.1
*	J	US-2001/0008452 A1	07-2001	Sugihara et al.	359/124
*	K	US-2001/0028760 A1	10-2001	Yaffe, Henry H.	385/27
*	L	US-6,310,709 B1	10-2001	Bergano, Neal S.	398/185
*	M	US-6,317,240 B1	11-2001	Penninckx et al.	398/147

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Morkel, P.R., "PMD-induced BER penalties in optically-amplified IM/DD lightwave systems", IEEE Electronics Letters, 12 May 1994, Vol 30, Iss 10, page 806-807
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/662,394		Applicant(s)/Patent Under Reexamination AKIYAMA ET AL.	
	Examiner DANNY W. LEUNG		Art Unit 2613	Page 2 of 4

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0018265 A1	02-2002	Graves, Alan F.	359/128
*	B	US-2002/0024704 A1	02-2002	Erdogan et al.	359/156
*	C	US-6,421,153 B1	07-2002	Way et al.	398/152
*	D	US-6,512,612 B1	01-2003	Fatehi et al.	398/49
*	E	US-6,570,682 B2	05-2003	Robinson et al.	398/20
*	F	US-2003/0202795 A1	10-2003	Garcia et al.	398/147
*	G	US-6,671,464 B1	12-2003	Kikuchi, Nobuhiko	398/65
*	H	US-6,671,045 B1	12-2003	Lee et al.	356/364
*	I	US-6,681,081 B2	01-2004	Mao, Xiaoping Charles	398/147
*	J	US-6,678,431 B2	01-2004	Han et al.	385/11
*	K	US-6,690,454 B2	02-2004	Kennedy et al.	356/73.1
*	L	US-6,710,904 B1	03-2004	Penninckx et al.	398/111
*	M	US-6,707,541 B1	03-2004	Noe, Reinhold	356/73.1

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/662,394		Applicant(s)/Patent Under Reexamination AKIYAMA ET AL.	
	Examiner DANNY W. LEUNG		Art Unit 2613	Page 3 of 4

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0067057 A1	04-2004	Akiyama et al.	398/026
*	B	US-6,792,168 B2	09-2004	Lanne et al.	385/11
*	C	US-2004/0202480 A1	10-2004	Weid et al.	398/147
*	D	US-6,807,321 B2	10-2004	Madsen, Christi Kay	385/11
*	E	US-6,813,021 B2	11-2004	Chung et al.	356/364
*	F	US-6,859,268 B2	02-2005	Chou et al.	356/73.1
*	G	US-6,885,820 B2	04-2005	Eder et al.	398/26
*	H	US-6,901,225 B1	05-2005	Noe, Reinhold	398/206
*	I	US-6,934,479 B2	08-2005	Sakamoto et al.	398/193
*	J	US-6,947,194 B2	09-2005	Matsumoto et al.	359/280
*	K	US-6,950,611 B2	09-2005	Erdogan et al.	398/152
*	L	US-7,006,736 B2	02-2006	Lee et al.	385/47
*	M	US-7,024,058 B2	04-2006	Han et al.	385/11

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/662,394		Applicant(s)/Patent Under Reexamination AKIYAMA ET AL.	
	Examiner DANNY W. LEUNG		Art Unit 2613	Page 4 of 4

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,024,111 B2	04-2006	Knox et al.	398/25
*	B	US-7,027,198 B2	04-2006	Yao, X. Steve	359/259
*	C	US-7,030,973 B2	04-2006	Rasmussen et al.	356/73.1
*	D	US-7,043,122 B2	05-2006	Han et al.	385/37
*	E	US-7,050,658 B2	05-2006	Chung et al.	385/1
*	F	US-7,067,795 B1	06-2006	Yan et al.	250/225
*	G	US-7,142,736 B2	11-2006	Patel et al.	385/12
*	H	US-7,203,428 B2	04-2007	Waarts et al.	398/204
*	I	US-7,218,436 B2	05-2007	Yao, X. Steve	359/259
*	J	US-7,308,204 B2	12-2007	Hayashi et al.	398/152
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.